

# Vacuum test fixture

## VA 3070S-2e/ZSK-10P-2e/i3070

Item 115202



GO TO PRODUCT

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Partner for Future Technology

- Vacuum test fixture with parallel lifting vacuum cassette
- Incl. fixture interface for Keysight-Testsystem i3070
- Incl. Alum-A transport handles
- Robust, maintenance-friendly design with outstanding service life
- Increased ease of use thanks to simple, intuitive handling
- For the assembly of items delivered unassembled, Refer to the drawings of the items specified in the parts list to assemble items

NEW

### Application

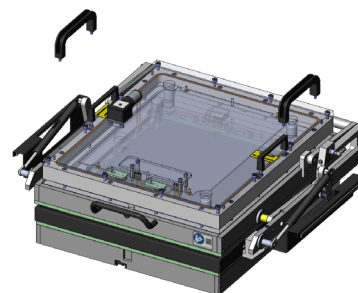
Typical service life of tip is approximately 25,000 load cycles (laboratory conditions)

### Version

- Probe plate made of 14 mm thick, deflection-resistant FR4
- Moving plate made of 8 mm thick FR3 with ESD-conductive surface
- Trusted, durable INGUN vacuum seals
- Incl. Alum-A transport handles
- Extensive perforations on the housing and plastic cover for mounting of optionally available stroke counters
- Optionally available locking units to secure the pressure plate

### Delivery

The fixture must be assembled upon delivery. This enables immediate DUT-specific machining. Refer to the drawings of the components specified in the part lists to assemble these correctly.



#### Note:

Customising guidelines INFO 4677 should be used for the professional customisation of vacuum test fixtures. Refer to customising guidelines INFO 4675 for the professional customisation of the keep-out zones.

#### Note:

The positions in the area L004/L008:S11/S30 and L232/L236:S49/S68 cannot be fitted with transfer pins due to the design of the intake ducts.

### General data

Test system interface:	Keysight i3070, small
Product group:	Vacuum test fixture (VA)
Main series:	VA xxxx
Subseries:	VA 30xx
Series:	VA 3070S
Size:	xx70S
Test fixture type:	Small stand-alone fixture, additional contacting unit, Keysight
Contact stroke generation:	Vacuum
Housing type:	Flat housing
Max. interface signals:	0
Interface blocks required:	No
Max. internal interface blocks:	0
Contacting direction:	ICT/FCT bottom, top
Max. contact force:	13,000 N [46,760 ozf]
Approx. parallel contact stroke:	12 mm [.472 in]
Weight:	32 kg [70.5 lbs]
Min. temperature:	10 °C [50 °F]
Max. temperature:	60 °C [140 °F]
Low voltage:	No
ESD-compliant:	No
RoHS-compliant:	Yes

### Technical data

Pushrod length:	15 mm [.59 in]
Test probe installation height, top:	16 mm [.629 in]
Test probe installation height, bottom:	16 mm [.629 in]
Test probe installation height, dual-stage, top:	21.5 mm [.846 in]
Test probe installation height, dual-stage, bottom:	21.5 mm [.846 in]
Free space above PCB:	10 mm [.393 in]
Standard version:	Yes
ESD version:	No
Radio frequency version:	No
Rigid pin version:	No
Dual-stage version:	Yes
Additional contacting unit (ZSK), top:	Yes
Useable area, additional contact unit (WxD):	260 x 300 mm [10.2 x 11.8 in]
Outer dimensions, closed (WxDxH):	631 x 534 x 209 mm [24.8 x 21 x 8.22 in]



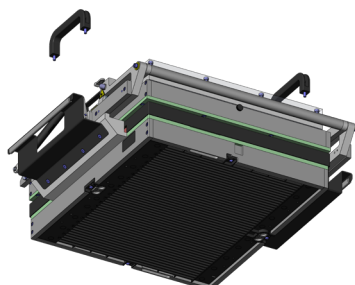
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### Accessories

Part no.	Designation	Version	Compatible with
115385	FB-VER-ADP-VA3070	Locking unit moving plate	VA 3070 versions without top unit
45000	PP-INGUN-F	Personality pin	VA 3070S/ST/L/LT versions
116613	EHZ-08-R-11-TR	Electric stroke counter	VA 3070S/ST/L/LT versions
11224	EHZ-08-R-49-OM	Electric stroke counter	VA 3070S/ST/L/LT versions
34865	EHZ-08-R-32-HE	Electric stroke counter	VA 3070S/ST/L/LT versions
1571	FED-10,0-16,0-97N-09,0	Pressure spring	VA 3070 single-stage versions (ICT)
1581	FED-10,0-21,5-100N-09,7	Pressure spring	VA 3070 dual-stage versions (ICT/FCT)
2579	HBS-01,0-10,0	Stroke-limiting disk	VA 3070 single-stage versions (ICT)
11890	HBS-05,0-07,0	Stroke-limiting disk	VA 3070 dual-stage versions (ICT/FCT)

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Prices and delivery times on request.  
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